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6-13-02



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

ATTY.'S DOCKET: ADIR=2

In re Application of:

Allon ADIR

Appln. No.: 10/041,671

Filed: January 10, 2002

For: NON-UNIQUE RESULTS IN  
DESIGN VERIFICATION BY  
TEST PROGRAMS

) Art Unit: 2123

) Examiner:

) Confirmation No. 2977

) Washington, D.C.

) May 8, 2002

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Technology Center 2100

INFORMATION DISCLOSURE STATEMENT [IDS]

Honorable Commissioner of Patents and Trademarks  
Washington, D.C. 20231

Sir :

This Information Disclosure Statement is submitted in accordance with 37 CFR §§1.97, 1.98, and it is requested that the information set forth in this statement and in the listed documents be considered during the pendency of the above- identified application, and any other application relying on the filing date of the above-identified application or cross- referencing it as a related application.

1. This IDS should be considered, in accordance with 37 CFR §1.97, as it is filed before the mailing date of a first office action on the merits.

2. In accordance with 37 CFR §1.98, this IDS includes a list (e.g., Form PTO/SB/08A) of all patents, publications, or other information submitted for consideration by the office, either incorporated into this IDS or as an attachment hereto. A copy of each document listed is attached.

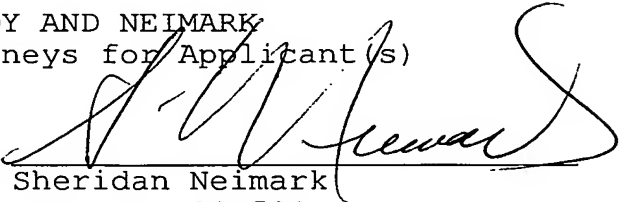
3. No explanation of relevance is necessary for documents in the English language (see reply to Comments 67 and 68 in the preamble to the final rules; 1135 OG 13 at 20).

4. In accordance with 37 CFR §§1.97(g) and (h), the filing of this IDS should not be construed as a representation that a search has been made or that information cited is, or is considered to be, material to patentability as defined in §1.56 (b), or that any cited document listed or attached is (or constitutes) prior art. Unless otherwise indicated, the date of publication indicated for an item is taken from the face of the item and Applicant(s) reserves the right to prove that the date of publication is in fact different.

Respectfully submitted,

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Substitute for form 1449A/PTO

**INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT**

(use as many sheets as necessary)

Sheet 1

of

1

**Complete if Known**

Application Number	10/041,671
Filing Date	January 10, 2002
First Named Inventor	Allon ADIR
Group Art Unit	2123
Examiner Name	
Attorney Docket Number	ADIR=2

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**U.S. PATENT DOCUMENTS**

Examiner Initials*	Cite No. <sup>1</sup>	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code <sup>2</sup> (if known)			
	AA	6,285,974	B1	MANDYMAN et al.	09-04-2001	

**OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS**

Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T <sup>2</sup>
	AB	A. SAHA et al., "A Stimulation-Based Approach to Architectural Verification of Multiprocessor System", IEEE, 1995, pp. 34-37	
	AC	A. CHANDRA et al., "AVPGEN - A Test Generator for Architecture Verification", IEEE Transactions on Very Large Scale Integration (VLSI), June 1995, pp. 188-200, vol. 3, no. 2	
	AD	Y. LICHTENSTEIN et al., "Model Based Test Generation for Processor Verification", Sixth Innovative Applications of Artificial Intelligence Conference, August 1994, pp. 83-94	
	AE	B. O'KRAFKA et al., "MPTG: A Portable Test Generator for Cache-Coherent Multiprocessors", IEEE, 1995, pp. 38-44	
	AF	Genesys - MP, User's Guide, Chapter 1-4, pp. 5-53, 1999	

Examiner  
SignatureDate  
Considered

\* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>1</sup> Unique citation designation number. <sup>2</sup> See attached Kinds of U.S. Patent Documents. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.